

MM74HC32 Quad 2-Input OR Gate

General Description

The MM74HC32 OR gates utilize advanced silicon-gate CMOS technology to achieve operating speeds similar to LS-TTL gates with the low power consumption of standard CMOS integrated circuits. All gates have buffered outputs providing high noise immunity and the ability to drive 10 LS-TTL loads. The 74HC logic family is functionally as well as pin-out compatible with the standard 74LS logic family.

All inputs are protected from damage due to static discharge by internal diode clamps to V_{CC} and ground.

Features

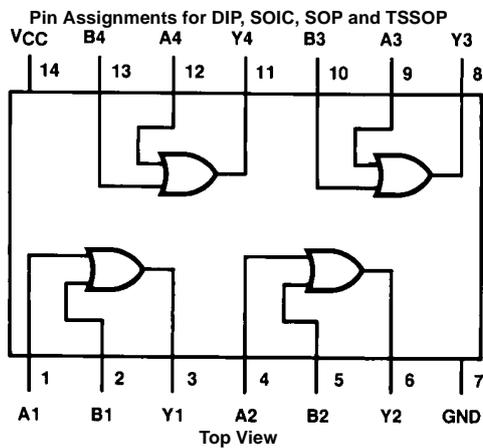
- Typical propagation delay: 10 ns
- Wide power supply range: 2–6V
- Low quiescent current: 20 μ A maximum (74HC Series)
- Low input current: 1 μ A maximum
- Fanout of 10 LS-TTL loads

Ordering Code:

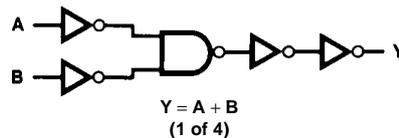
Order Number	Package Number	Package Description
MM74HC32M	M14A	14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-120, 0.150" Narrow
MM74HC32SJ	M14D	14-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
MM74HC32MTC	MTC14	14-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide
MM74HC32N	N14A	14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide

Devices also available in Tape and Reel. Specify by appending suffix letter "X" to the ordering code.

Connection Diagram



Logic Diagram



Absolute Maximum Ratings (Note 1)			Recommended Operating Conditions			
Supply Voltage (V_{CC})	-0.5 to +7.0V		Min	Max	Units	
DC Input Voltage (V_{IN})	-1.5 to $V_{CC} + 1.5V$	Supply Voltage (V_{CC})	2	6	V	
DC Output Voltage (V_{OUT})	-0.5 to $V_{CC} + 0.5V$	DC Input or Output Voltage	0	V_{CC}	V	
Clamp Diode Current (I_{IK}, I_{OK})	± 20 mA	(V_{IN}, V_{OUT})				
DC Output Current, per pin (I_{OUT})	± 25 mA	Operating Temperature Range (T_A)	-40	+85	$^{\circ}C$	
DC V_{CC} or GND Current, per pin (I_{CC})	± 50 mA	Input Rise or Fall Times				
Storage Temperature Range (T_{STG})	-65 $^{\circ}C$ to +150 $^{\circ}C$	(t_r, t_f) $V_{CC} = 2.0V$			1000	ns
Power Dissipation (P_D)		$V_{CC} = 4.5V$			500	ns
(Note 3)	600 mW	$V_{CC} = 6.0V$			400	ns
S.O. Package only	500 mW					
Lead Temperature (T_L)						
(Soldering 10 seconds)	260 $^{\circ}C$					

Note 1: Absolute Maximum Ratings are those values beyond which damage to the device may occur.

Note 2: Unless otherwise specified all voltages are referenced to ground.

Note 3: Power Dissipation temperature derating — plastic "N" package: -12 mW/ $^{\circ}C$ from 65 $^{\circ}C$ to 85 $^{\circ}C$.

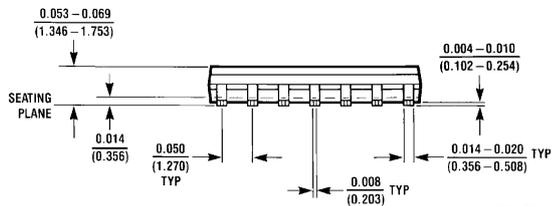
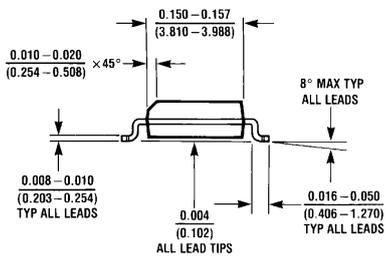
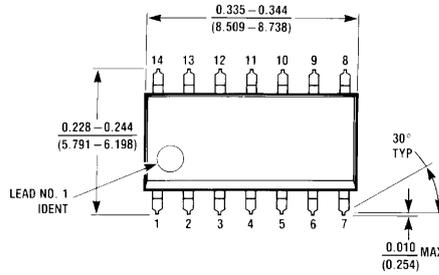
DC Electrical Characteristics (Note 4)

Symbol	Parameter	Conditions	V_{CC}	$T_A = 25^{\circ}C$		$T_A = -40$ to $85^{\circ}C$		Units
				Typ	Guaranteed Limits			
V_{IH}	Minimum HIGH Level Input Voltage		2.0V		1.5	1.5	V	
			4.5V		3.15	3.15	V	
			6.0V		4.2	4.2	V	
V_{IL}	Maximum LOW Level Input Voltage		2.0V		0.5	0.5	V	
			4.5V		1.35	1.35	V	
			6.0V		1.8	1.8	V	
V_{OH}	Minimum HIGH Level Output Voltage	$V_{IN} = V_{IH}$ or V_{IL} $ I_{OUT} \leq 20 \mu A$	2.0V	2.0	1.9	1.9	V	
			4.5V	4.5	4.4	4.4	V	
			6.0V	6.0	5.9	5.9	V	
		4.5V	$V_{IN} = V_{IH}$ or V_{IL} $ I_{OUT} \leq 4.0$ mA $ I_{OUT} \leq 5.2$ mA	4.7	3.98	3.84	V	
				5.2	5.48	5.34	V	
V_{OL}	Maximum LOW Level Output Voltage	$V_{IN} = V_{IL}$ $ I_{OUT} \leq 20 \mu A$	2.0V	0	0.1	0.1	V	
			4.5V	0	0.1	0.1	V	
			6.0V	0	0.1	0.1	V	
		4.5V	$V_{IN} = V_{IL}$ $ I_{OUT} \leq 4.0$ mA $ I_{OUT} \leq 5.2$ mA	0.2	0.26	0.33	V	
				0.2	0.26	0.33	V	
I_{IN}	Maximum Input Current	$V_{IN} = V_{CC}$ or GND	6.0V		± 0.1	± 1.0	μA	
I_{CC}	Maximum Quiescent Supply Current	$V_{IN} = V_{CC}$ or GND $I_{OUT} = 0 \mu A$	6.0V		2.0	20	μA	

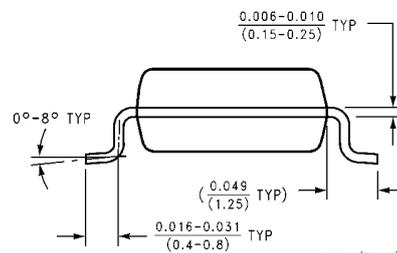
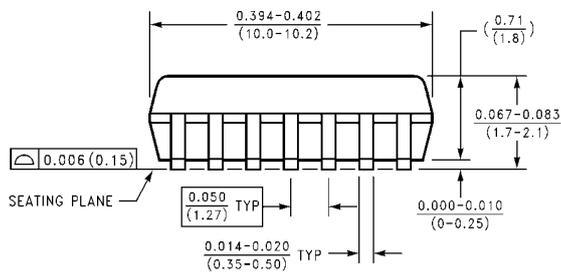
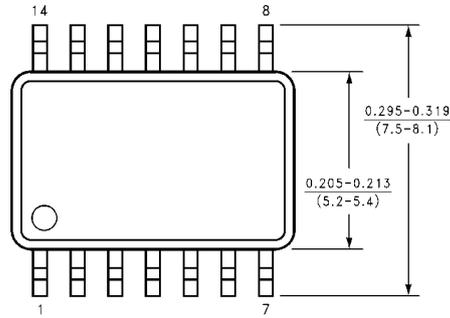
Note 4: For a power supply of 5V $\pm 10\%$ the worst case output voltages (V_{OH} and V_{OL}) occur for HC at 4.5V. Thus the 4.5V values should be used when designing with this supply. Worst case V_{IH} and V_{IL} occur at $V_{CC} = 5.5V$ and 4.5V respectively. (The V_{IH} value at 5.5V is 3.85V.) The worst case leakage current (I_{IN} , I_{CC} , and I_{OZ}) occur for CMOS at the higher voltage and so the 6.0V values should be used.

AC Electrical Characteristics							
$V_{CC} = 5V, T_A = 25^{\circ}C, C_L = 15 \text{ pF}, t_r = t_f = 6 \text{ ns}$							
Symbol	Parameter	Conditions	Typ	Guaranteed Limit	Units		
t_{PHL}, t_{PLH}	Maximum Propagation Delay		10	18	ns		
AC Electrical Characteristics							
$V_{CC} = 2.0V \text{ to } 6.0V, C_L = 50 \text{ pF}, t_r = t_f = 6 \text{ ns}$ (unless otherwise specified)							
Symbol	Parameter	Conditions	V_{CC}	$T_A = 25^{\circ}C$		$T_A = -40 \text{ to } 85^{\circ}C$	Units
				Typ	Guaranteed Limits		
t_{PHL}, t_{PLH}	Maximum Propagation Delay		2.0V	30	100	125	ns
			4.5V	12	20	25	ns
			6.0V	9	17	21	ns
t_{TLH}, t_{THL}	Maximum Output Rise and Fall Time		2.0V	30	75	95	ns
			4.5V	8	15	19	ns
			6.0V	7	13	16	ns
C_{PD}	Power Dissipation Capacitance (Note 5)	(per gate)		50			pF
C_{IN}	Maximum Input Capacitance			5	10	10	pF
<p>Note 5: C_{PD} determines the no load dynamic power consumption, $P_D = C_{PD} V_{CC}^2 f + I_{CC} V_{CC}$, and the no load dynamic current consumption, $I_S = C_{PD} V_{CC} f + I_{CC}$.</p>							

Physical Dimensions inches (millimeters) unless otherwise noted

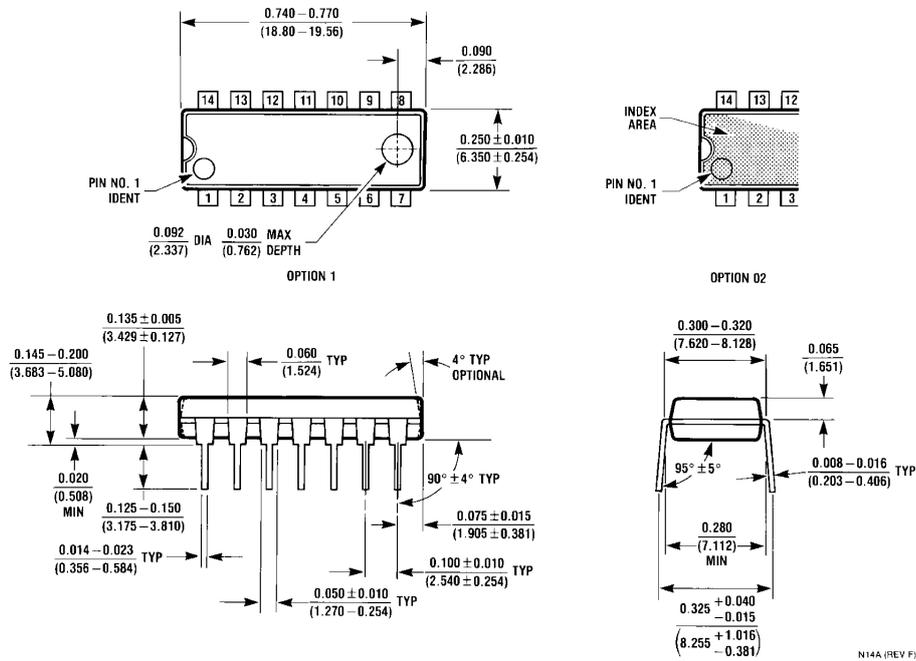


14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-120, 0.150" Narrow Package Number M14A



14-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide Package Number M14D

Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide Package Number N14A

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